INFORMATION CITED BY APPLICANT(S) THAT MAY BE MATERIAL TO THE PROSECUTION OF THE SUBJECT APPLICATION

Applicant:

F.M. Schellenberg et al.

Attorney Docket No. MEGC122529

Application No.: --

Group Art Unit: --

Filed:

4

March 26, 2004

Examiner: --

Title:

CREATING PHOTOLITHOGRAPHIC MASKS

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*Examiner				
Initial	ID	Document No.	Date	Name
•	U1	5,364,716	11/15/1994	Nakagawa et al.
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	U3	5,636,131	06/03/1997	Liebmann et al.
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*Examiner Initial	Cite No.	Document No.	Kind Code	Publication Date (mm/dd/yyyy)	Country	English Abstract Translation Provided Provided
	F1	DE 41 21 564	A1	01/09/1992	Germany	
	F2	EP 0 698 916	A2	02/28/1996	EPO	
	F3	WO 99/14636	A1	03/25/1999	PCT	

OTHER INFORMATION (Including Author, Title, Date, Pertinent Pages, Etc.)

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	O1	Marc D. Levenson, <i>Improving Resolution in Photolithography with a Phase-Shifting Mask</i> , IEEE TRANSACTIONS ON ELECTRON DEVICES, Vol. ED-29, No. 12, December 1982.
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	O3	Kazuyuki Inokuchi, Tadashi Saito, Hideyuki Jinbo, Yoshio Yamashita, and Yoshiaki Sano, Sub-Quarter Micron Gate Fabrication Process Using Phase-Shifting Mask for Microwave GaAs Devices, JAPANESE JOURNAL OF APPLIED PHYSICS, Vol. 30, No. 12B, December 1991, pp. 3818-3821.
	O4	B. J. Lin, <i>Phase-Shifting Masks Gain an Edge</i> , IEEE CIRCUITS & DEVICES, March 1993, pp. 28-35.
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*Examiner: Initial if reference considered, whether or not citation is in conformance with M.P.E.P. § 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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